INTEGRATED CIRCUITS

DATA SHEET

74HC04; 74HCT04 Hex inverter

Product specification Supersedes data of 1993 Sep 01 2003 Jul 23





Hex inverter 74HC04; 74HCT04

FEATURES

- Complies with JEDEC standard no. 8-1A
- ESD protection: HBM EIA/JESD22-A114-A exceeds 2000 V MM EIA/JESD22-A115-A exceeds 200 V.
- Specified from -40 to +85 °C and -40 to +125 °C.

DESCRIPTION

The 74HC/HCT04 are high-speed Si-gate CMOS devices and are pin compatible with low power Schottky TTL (LSTTL). They are specified in compliance with JEDEC standard no. 7A. The 74HC/HCT04 provide six inverting buffers.

QUICK REFERENCE DATA

GND = 0 V; $T_{amb} = 25 \, ^{\circ}C$; $t_r = t_f \le 6.0 \, \text{ns}$.

SYMBOL	PARAMETER	CONDITIONS	TYP	UNIT	
	FARAMETER	CONDITIONS	HC04	НСТ04	UNIT
t _{PHL} /t _{PLH}	propagation delay nA to nY	C _L = 15 pF; V _{CC} = 5 V	7	8	ns
Cı	input capacitance		3.5	3.5	pF
C _{PD}	power dissipation capacitance per gate	notes 1 and 2	21	24	pF

Notes

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

$$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$$
 where:

 f_i = input frequency in MHz;

f_o = output frequency in MHz;

C_L = output load capacitance in pF;

V_{CC} = supply voltage in Volts;

N = total load switching outputs;

 $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs.

2. For 74HC04: the condition is $V_I = GND$ to V_{CC} .

For 74HCT04: the condition is $V_I = GND$ to $V_{CC} - 1.5 \text{ V}$.

FUNCTION TABLE

See note 1.

INPUT	ОИТРИТ
nA	nY
L	Н
Н	L

Note

- 1. H = HIGH voltage level;
 - L = LOW voltage level.

Hex inverter

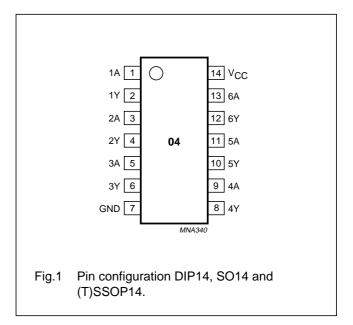
74HC04; 74HCT04

ORDERING INFORMATION

TVDE NUMBER		PACKAGE								
TYPE NUMBER	TEMPERATURE RANGE	PINS	PACKAGE	MATERIAL	CODE					
74HC04N	−40 to +125 °C	14	DIP14	plastic	SOT27-1					
74HCT04N	−40 to +125 °C	14	DIP14	plastic	SOT27-1					
74HC04D	−40 to +125 °C	14	SO14	plastic	SOT108-1					
74HCT04D	−40 to +125 °C	14	SO14	plastic	SOT108-1					
74HC04DB	−40 to +125 °C	14	SSOP14	plastic	SOT337-1					
74HCT04DB	−40 to +125 °C	14	SSOP14	plastic	SOT337-1					
74HC04PW	−40 to +125 °C	14	TSSOP14	plastic	SOT402-1					
74HCT04PW	−40 to +125 °C	14	TSSOP14	plastic	SOT402-1					
74HC04BQ	−40 to +125 °C	14	DHVQFN14	plastic	SOT762-1					
74HCT04BQ	–40 to +125 °C	14	DHVQFN14	plastic	SOT762-1					

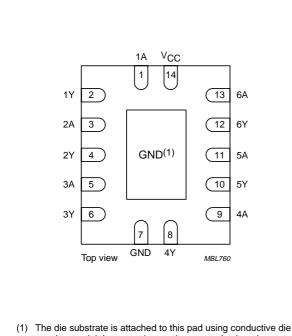
PINNING

PIN	SYMBOL	DESCRIPTION
1	1A	data input
2	1Y	data output
3	2A	data input
4	2Y	data output
5	3A	data input
6	3Y	data output
7	GND	ground (0 V)
8	4Y	data output
9	4A	data input
10	5Y	data output
11	5A	data input
12	6Y	data output
13	6A	data input
14	V _{CC}	supply voltage



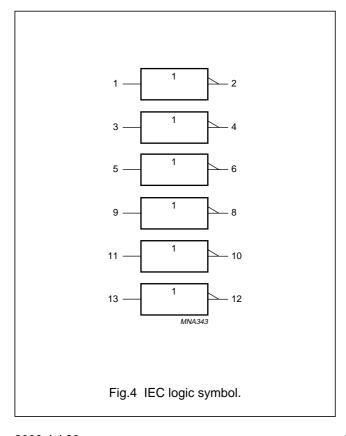
Hex inverter

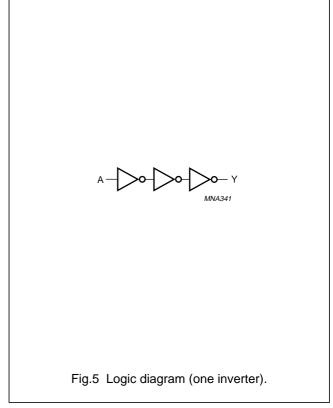
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attach material. It can not be used as a supply pin or input.

Fig.2 Pin configuration DHVQFN14.





Hex inverter 74HC04; 74HCT04

RECOMMENDED OPERATING CONDITIONS

CVMBOL	PARAMETER	CONDITIONS	74HC04			74HCT04			UNIT
SYMBOL	TANAMETER	CONDITIONS	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	UNII
V _{CC}	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
VI	input voltage		0	_	V _{CC}	0	_	V _{CC}	V
Vo	output voltage		0	_	Vcc	0	_	V _{CC}	V
T _{amb}	ambient temperature	see DC and AC characteristics per device	-40	+25	+125	-40	+25	+125	°C
t _r , t _f	input rise and fall times	V _{CC} = 2.0 V	_	_	1000	_	_	_	ns
		V _{CC} = 4.5 V	_	6.0	500	_	6.0	500	ns
		V _{CC} = 6.0 V	_	_	400	_	_	_	ns

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{CC}	supply voltage		-0.5	+7.0	V
I _{IK}	input diode current	$V_{I} < -0.5 \text{ V or } V_{I} > V_{CC} + 0.5 \text{ V}$	_	±20	mA
I _{OK}	output diode current	$V_{O} < -0.5 \text{ V or } V_{O} > V_{CC} + 0.5 \text{ V}$	_	±20	mA
Io	output source or sink current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$	_	±25	mA
I _{CC} , I _{GND}	V _{CC} or GND current		_	±50	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	power dissipation				
	DIP14 package	$T_{amb} = -40 \text{ to } +125 ^{\circ}\text{C}; \text{ note } 1$	_	750	mW
	other packages	$T_{amb} = -40 \text{ to } +125 ^{\circ}\text{C}; \text{ note } 2$	_	500	mW

Notes

- 1. For DIP14 packages: above 70 °C derate linearly with 12 mW/K.
- 2. For SO14 packages: above 70 °C derate linearly with 8 mW/K.

For SSOP14 and TSSOP14 packages: above 60 °C derate linearly with 5.5 mW/K.

For DHVQFN14 packages: above 60 °C derate linearly with 4.5 mW/K.

Hex inverter 74HC04; 74HCT04

DC CHARACTERISTICS

Type 74HC04

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

CVMDOL	DADAMETED	TEST CONDITIO	NS	NAIN!	TVD	BAAY	LINUT
SYMBOL	PARAMETER	OTHER	V _{CC} (V)	MIN.	TYP.	MAX.	UNIT
T _{amb} = 25 °	C			•			•
V _{IH}	HIGH-level input voltage		2.0	1.5	1.2	_	V
			4.5	3.15	2.4	_	V
			6.0	4.2	3.2	_	V
V _{IL}	LOW-level input voltage		2.0	_	0.8	0.5	V
			4.5	_	2.1	1.35	V
			6.0	_	2.8	1.8	V
V _{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		$I_{O} = -20 \mu\text{A}$	2.0	1.9	2.0	_	V
		$I_{O} = -20 \mu\text{A}$	4.5	4.4	4.5	_	V
		$I_{O} = -4.0 \text{ mA}$	4.5	3.98	4.32	-	V
		$I_{O} = -20 \mu\text{A}$	6.0	5.9	6.0	_	V
		$I_{O} = -5.2 \text{ mA}$	6.0	5.48	5.81	_	V
V _{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		I _O = 20 μA	2.0	_	0	0.1	V
		I _O = 20 μA	4.5	_	0	0.1	V
		$I_{O} = 4.0 \text{ mA}$	4.5	_	0.15	0.26	V
		I _O = 20 μA	6.0	_	0	0.1	V
		I _O = 5.2 mA	6.0	_	0.16	0.26	V
ILI	input leakage current	$V_I = V_{CC}$ or GND	6.0	_	0.1	±0.1	μΑ
I _{OZ}	3-state output OFF current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND}$	6.0	_	_	±.0.5	μА
Icc	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	6.0	_	_	2	μΑ

Hex inverter 74HC04; 74HCT04

CVMDOL	PARAMETER	TEST CONDITIO	NS	MIN.	TYP.	MAX.	UNIT
SYMBOL		OTHER	V _{CC} (V)	ivilia.			
T _{amb} = -40	to +85 °C			•			
V _{IH}	HIGH-level input voltage		2.0	1.5	-	_	V
			4.5	3.15	_	_	V
			6.0	4.2	-	_	V
V _{IL}	LOW-level input voltage		2.0	_	-	0.5	V
			4.5	_	_	1.35	V
			6.0	_	-	1.8	V
V _{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		$I_{O} = -20 \mu\text{A}$	2.0	1.9	_	_	V
		$I_{O} = -20 \mu\text{A}$	4.5	4.4	_	_	V
		$I_{O} = -4.0 \text{ mA}$	4.5	3.84	_	_	V
		$I_{O} = -20 \mu\text{A}$	6.0	5.9	_	_	V
		$I_{O} = -5.2 \text{ mA}$	6.0	5.34	_	-	V
V _{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		I _O = 20 μA	2.0	_	_	0.1	V
		I _O = 20 μA	4.5	_	_	0.1	V
		$I_{O} = 4.0 \text{ mA}$	4.5	_	_	0.33	V
		I _O = 20 μA	6.0	_	_	0.1	V
		I _O = 5.2 mA	6.0	_	_	0.33	V
ILI	input leakage current	$V_I = V_{CC}$ or GND	6.0	_	-	±1.0	μΑ
I _{OZ}	3-state output OFF current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND}$	6.0	_	_	±.5.0	μΑ
I _{CC}	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	6.0	_	_	20	μΑ

Hex inverter 74HC04; 74HCT04

CVMDOL	DADAMETED	TEST CONDITIO	NS	MIN.	TYP.	MAX.	
SYMBOL	PARAMETER	OTHER	V _{CC} (V)	IVIIIV.			UNIT
T _{amb} = -40	to +125 °C						•
V _{IH}	HIGH-level input voltage		2.0	1.5	_	_	V
			4.5	3.15	_	_	V
			6.0	4.2	_	_	V
V _{IL}	LOW-level input voltage		2.0	_	_	0.5	V
			4.5	_	_	1.35	V
			6.0	_	_	1.8	V
V _{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		$I_{O} = -20 \mu A$	2.0	1.9	_	_	V
		$I_{O} = -20 \mu A$	4.5	4.4	_	_	V
		$I_{O} = -20 \mu A$	6.0	5.9	_	_	V
		$I_{O} = -4.0 \text{ mA}$	4.5	3.7	_	_	V
		$I_{O} = -5.2 \text{ mA}$	6.0	5.2	_	_	V
V_{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		I _O = 20 μA	2.0	_	_	0.1	V
		I _O = 20 μA	4.5	_	_	0.1	V
		I _O = 20 μA	6.0	_	_	0.1	V
		$I_{O} = 4.0 \text{ mA}$	4.5	_	_	0.4	V
		I _O = 5.2 mA	6.0	_	_	0.4	V
ILI	input leakage current	$V_I = V_{CC}$ or GND	6.0	_	_	±1.0	μΑ
I _{OZ}	3-state output OFF current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND}$	6.0	_	_	±10.0	μΑ
I _{CC}	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	6.0	_	_	40	μΑ

Hex inverter 74HC04; 74HCT04

Type 74HCT04At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

CVMDO	DADAMETER	TEST CONDI	NAINI	TVD	MAX.	114117	
SYMBOL	PARAMETER	OTHER	V _{CC} (V)	MIN.	TYP.	WAX.	UNIT
T _{amb} = 25 °	Ċ		-	•	1		•
V _{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	1.6	_	V
V _{IL}	LOW-level input voltage		4.5 to 5.5	_	1.2	0.8	V
V _{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		$I_{O} = -20 \mu A$	4.5	4.4	4.5	_	V
		$I_{O} = -4.0 \text{ mA}$	4.5	3.84	4.32	_	V
V _{OL}	LOW-level output voltage	$V_I = V_{IH} \text{ or } V_{IL}$					
		$I_0 = 20 \mu\text{A}$	4.5	_	0	0.1	V
		$I_{O} = 4.0 \text{ mA}$	4.5	_	0.15	0.26	V
ILI	input leakage current	$V_I = V_{CC}$ or GND	5.5	_	_	±0.1	μΑ
l _{OZ}	3-state output OFF current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND};$ $I_O = 0$	5.5	_	_	±0.5	μА
I _{CC}	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	5.5	_	_	2	μΑ
ΔI_{CC}	additional supply current per input	$V_I = V_{CC} - 2.1 \text{ V};$ $I_O = 0$	4.5 to 5.5	_	120	432	μΑ
T _{amb} = -40	to +85 °C			•			•
V _{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	_	_	V
V _{IL}	LOW-level input voltage		4.5 to 5.5	_	_	0.8	V
V _{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}			_		
		$I_{O} = -20 \mu A$	4.5	4.4	_	_	V
		$I_{O} = -4.0 \text{ mA}$	4.5	3.84	_	_	V
V _{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}			_		
		$I_0 = 20 \mu A$	4.5	_	_	0.1	V
		$I_{O} = 4.0 \text{ mA}$	4.5	_	_	0.33	V
ILI	input leakage current	$V_I = V_{CC}$ or GND	5.5	_	_	±1.0	μΑ
l _{OZ}	3-state output OFF current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND};$ $I_O = 0$	5.5	_	-	±5.0	μА
I _{CC}	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	5.5	_	_	20	μΑ
Δl _{CC}	additional supply current per input	$V_I = V_{CC} - 2.1 \text{ V};$ $I_O = 0$	4.5 to 5.5	_	_	540	μΑ

Hex inverter 74HC04; 74HCT04

CVMDOL	PARAMETER	TEST CONDI	NAINI	TVD	MAX.		
SYMBOL		OTHER	V _{CC} (V)	MIN.	TYP.	WAA.	UNIT
T _{amb} = -40	to +125 °C	•			•	•	•
V _{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	_	_	V
V _{IL}	LOW-level input voltage		4.5 to 5.5	_	_	0.8	V
V _{OH}	HIGH-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		$I_{O} = -20 \mu\text{A}$	4.5	4.4	_	_	V
		$I_{O} = -4.0 \text{ mA}$	4.5	3.7	_	_	V
V _{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}					
		$I_{O} = 20 \mu A$	4.5	_	_	0.1	V
		$I_{O} = 4.0 \text{ mA}$	4.5	_	_	0.4	V
ILI	input leakage current	$V_I = V_{CC}$ or GND	5.5	_	_	±1.0	μΑ
I _{OZ}	3-state output OFF current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND};$ $I_O = 0$	5.5	_	_	±10	μΑ
Icc	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	5.5	_	_	40	μА
ΔI_{CC}	additional supply current per input	$V_{I} = V_{CC} - 2.1 \text{ V};$ $I_{O} = 0$	4.5 to 5.5	_	_	590	μА

Hex inverter 74HC04; 74HCT04

AC CHARACTERISTICS

Family 74HC04

GND = 0 V; $t_r = t_f \le 6.0$ ns; $C_L = 50$ pF.

OVMDOL	DADAMETED	TEST CONDI	TIONS	24121	TYP.	MAX.	
SYMBOL	PARAMETER	WAVEFORMS	V _{CC} (V)	MIN.			UNIT
T _{amb} = 25 °C	;	•			•		•
t _{PHL} /t _{PLH}	propagation delay	see Figs 6 and 7	2.0	_	25	85	ns
	nA to nY		4.5	_	9	17	ns
			6.0	_	7	14	ns
t _{THL} /t _{TLH} output transi	output transition time	see Figs 6 and 7	2.0	_	19	75	ns
			4.5	_	7	15	ns
			6.0	_	6	13	ns
T _{amb} = -40 to	o +85 °C						
t _{PHL} /t _{PLH} propagation delay nA to nY	see Figs 6 and 7	2.0	_	_	105	ns	
	nA to nY		4.5	_	_	21	ns
			6.0	_	_	18	ns
t _{THL} /t _{TLH}	output transition time	see Figs 6 and 7	2.0	_	_	95	ns
			4.5	_	_	19	ns
			6.0	_	_	16	ns
T _{amb} = -40 to	o +125 °C						
t _{PHL} /t _{PLH}	propagation delay	see Figs 6 and 7	2.0	_	_	130	ns
	nA to nY		4.5	_	_	26	ns
			6.0	_	_	22	ns
t _{THL} /t _{TLH}	output transition time	see Figs 6 and 7	2.0	_	_	110	ns
			4.5	_	_	22	ns
			6.0	_	_	19	ns

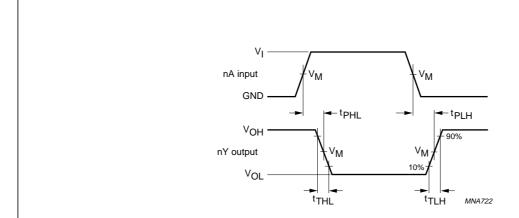
Hex inverter 74HC04; 74HCT04

Family 74HCT04

GND = 0 V; $t_r = t_f \le 6.0$ ns; $C_L = 50$ pF.

CVMDOL	DADAMETED	TEST CONDI	TIONS	BAINI	TVD	MAY	LINUT
SYMBOL	PARAMETER	WAVEFORMS	V _{CC} (V)	MIN.	TYP.	MAX.	UNIT
T _{amb} = 25 °C	•	•	•		•	-	•
t _{PHL} /t _{PLH}	propagation delay nA to nY	see Figs 6 and 7	4.5	_	10	19	ns
t _{THL} /t _{TLH}	output transition time	see Figs 6 and 7	4.5	_	7	15	ns
T _{amb} = -40 to	+85 °C		•	•	•	•	•
t _{PHL} /t _{PLH}	propagation delay nA to nY	see Figs 6 and 7	4.5	_	_	24	ns
t _{THL} /t _{TLH}	output transition time	see Figs 6 and 7	4.5	_	_	19	ns
T _{amb} = -40 to	+125 °C		•		•	•	•
t _{PHL} /t _{PLH}	propagation delay nA to nY	see Figs 6 and 7	4.5	_	_	29	ns
t _{THL} /t _{TLH}	output transition time	see Figs 6 and 7	4.5	_	_	22	ns

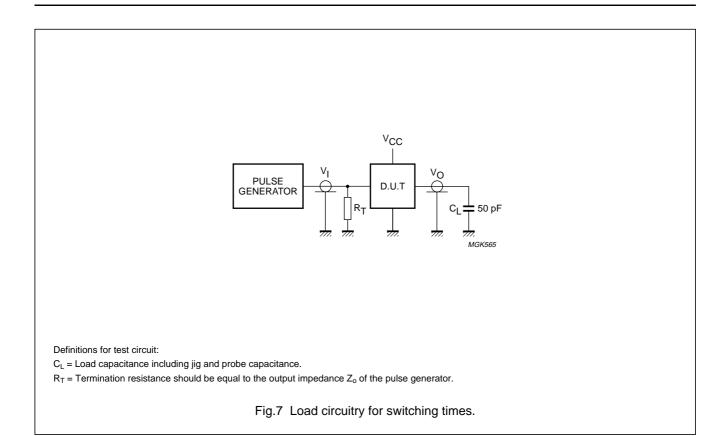
AC WAVEFORMS



For 74HC04: V_M = 50%; V_I = GND to V_{CC} . For 74HCT04: V_M = 1.3 V; V_I = GND to 3.0 V.

Fig.6 Waveforms showing the data input (nA) to data output (nY) propagation delays and the output transition times.

Hex inverter 74HC04; 74HCT04

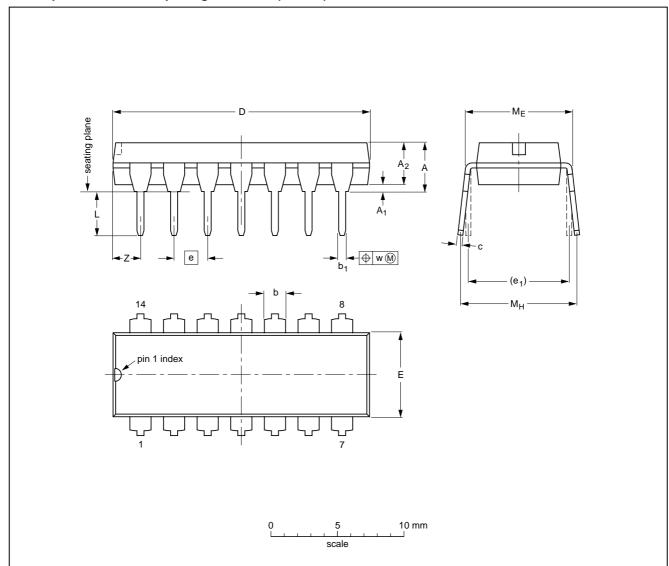


Hex inverter 74HC04; 74HCT04

PACKAGE OUTLINES

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	С	D ⁽¹⁾	E (1)	е	e ₁	L	ME	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.02	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

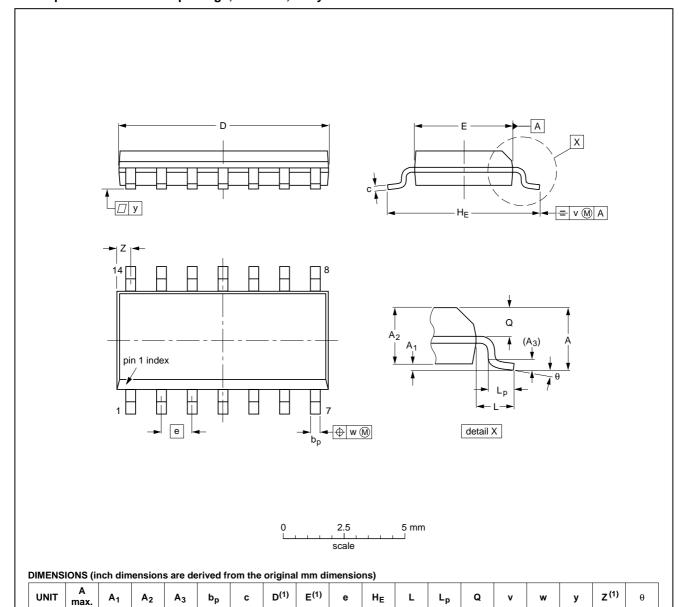
OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001	SC-501-14		99-12-27 03-02-13

Hex inverter

74HC04; 74HCT04

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



Note

mm

inches

0.25

0.010

0.004

0.057

0.049

1.75

0.069

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

0.019 0.0100 0.014 0.0075 8.75

0.35

0.34

OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT108-1	076E06	MS-012			99-12-27 03-02-19

1.27

0.05

0.244

0.228

3.8

0.16

0.15

1.05

0.041

0.039

0.016

0.028

0.024

0.25

0.01

0.25

0.01

0.004

0°

0.028

0.012

2003 Jul 23 15

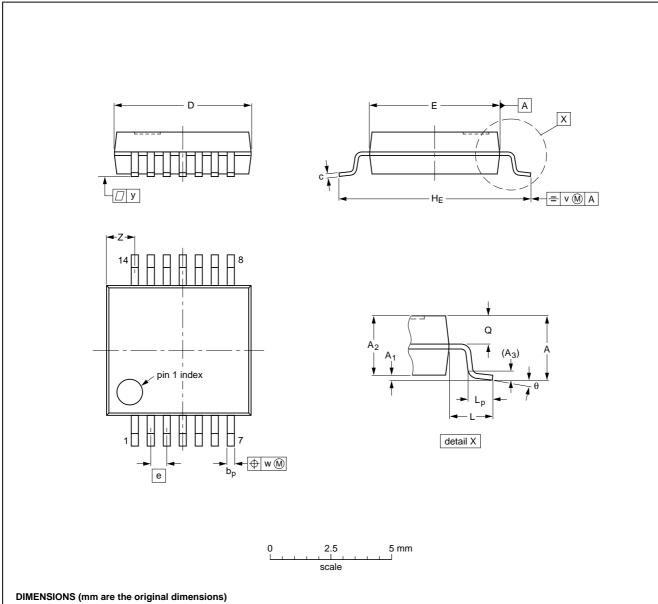
0.25

0.01

Hex inverter 74HC04; 74HCT04

SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	2	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	6.4 6.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	1.4 0.9	8° 0°

Note

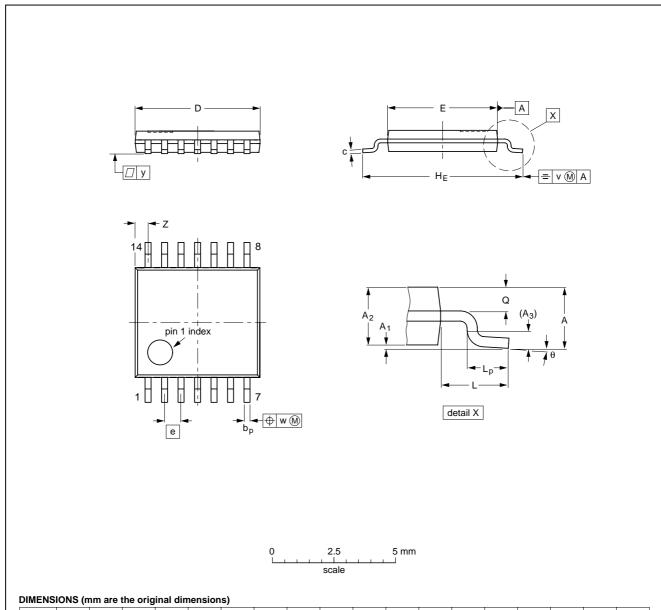
1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT337-1		MO-150			99-12-27 03-02-19

Hex inverter 74HC04; 74HCT04

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E (2)	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8° 0°

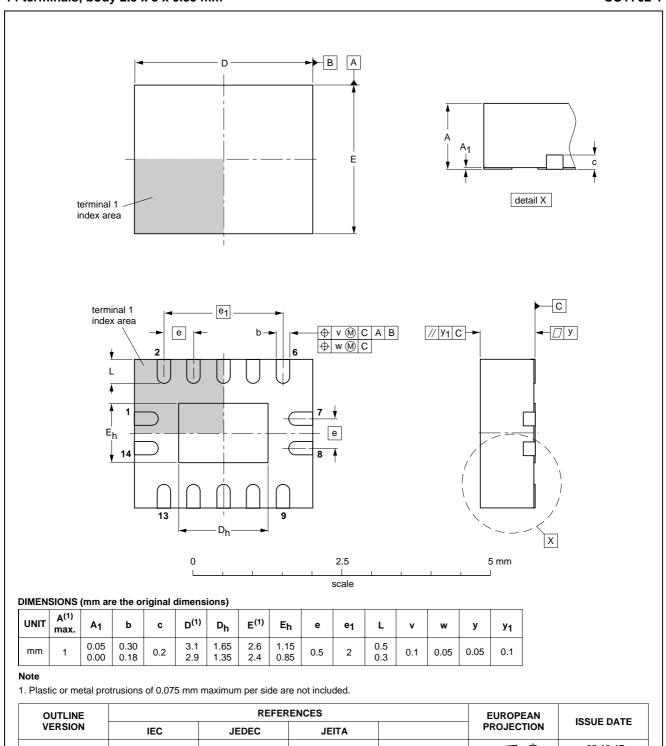
Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT402-1		MO-153			99-12-27 03-02-18

74HC04; 74HCT04 Hex inverter

DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; SOT762-1 14 terminals; body 2.5 x 3 x 0.85 mm



OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT762-1		MO-241			02-10-17 03-01-27

2003 Jul 23 18

Hex inverter 74HC04; 74HCT04

DATA SHEET STATUS

LEVEL	DATA SHEET STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾⁽³⁾	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

Notes

- 1. Please consult the most recently issued data sheet before initiating or completing a design.
- 2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
- 3. For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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Contact information

For additional information please visit http://www.semiconductors.philips.com. Fax: +31 40 27 24825 For sales offices addresses send e-mail to: sales.addresses@www.semiconductors.philips.com.

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